## Abstract of the Disclosure:

A method of determining the critical path of a circuit includes first determining the paths, their mean path transit times and their path transit time fluctuations. Paths having similar statistical parameters are combined to form one path group. For each path group, a statistical group figure is, then, calculated and, for the totality of paths considered, a statistical total figure is calculated. Finally, the critical paths of the circuit are determined by taking into consideration the total figure, comparing the group figures at or above a critical path transit time Tc.

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